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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	3411
Number of Logic Elements/Cells	43661
Total RAM Bits	2138112
Number of I/O	358
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	676-BGA
Supplier Device Package	676-FBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6slx45-n3fg676i

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description					Units
V_{IN} and V_{TS} ⁽³⁾	I/O input voltage or voltage applied to 3-state output, relative to GND ⁽⁴⁾	All user and dedicated I/Os	Commercial	DC	–0.60 to 4.10	V
				20% overshoot duration	–0.75 to 4.25	V
				8% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
			Industrial	DC	–0.60 to 3.95	V
				20% overshoot duration	–0.75 to 4.15	V
				4% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
			Expanded (Q)	DC	–0.60 to 3.95	V
				20% overshoot duration	–0.75 to 4.15	V
				4% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
		Restricted to maximum of 100 user I/Os	Commercial	20% overshoot duration	–0.75 to 4.35	V
				15% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
				10% overshoot duration	–0.75 to 4.45	V
			Industrial	20% overshoot duration	–0.75 to 4.25	V
				10% overshoot duration	–0.75 to 4.35	V
				8% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
			Expanded (Q)	20% overshoot duration	–0.75 to 4.25	V
				10% overshoot duration	–0.75 to 4.35	V
				8% overshoot duration ⁽⁵⁾	–0.75 to 4.40	V
T_{STG}	Storage temperature (ambient)				–65 to 150	°C
T_{SOL}	Maximum soldering temperature ⁽⁶⁾ (TQG144, CPG196, CSG225, CSG324, CSG484, and FTG256)				+260	°C
	Maximum soldering temperature ⁽⁶⁾ (Pb-free packages: FGG484, FGG676, and FGG900)				+250	°C
	Maximum soldering temperature ⁽⁶⁾ (Pb packages: CS484, FT256, FG484, FG676, and FG900)				+220	°C
T_j	Maximum junction temperature ⁽⁶⁾				+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- When programming eFUSE, $V_{FS} \leq V_{CCAUX}$. Requires up to 40 mA current. For read mode, V_{FS} can be between GND and 3.45 V.
- I/O absolute maximum limit applied to DC and AC signals. Overshoot duration is the percentage of a data period that the I/O is stressed beyond 3.45V.
- For I/O operation, refer to [UG381](#): *Spartan-6 FPGA SelectIO Resources User Guide*.
- Maximum percent overshoot duration to meet 4.40V maximum.
- For soldering guidelines and thermal considerations, see [UG385](#): *Spartan-6 FPGA Packaging and Pinout Specification*.

Table 2: Recommended Operating Conditions⁽¹⁾

Symbol	Description			Min	Typ	Max	Units
V _{CCINT}	Internal supply voltage relative to GND	-3, -3N, -2	Standard performance ⁽²⁾	1.14	1.2	1.26	V
		-3, -2	Extended performance ⁽²⁾	1.2	1.23	1.26	V
		-1L	Standard performance ⁽²⁾	0.95	1.0	1.05	V
V _{CCAUX} ⁽³⁾⁽⁴⁾	Auxiliary supply voltage relative to GND	V _{CCAUX} = 2.5V ⁽⁵⁾		2.375	2.5	2.625	V
		V _{CCAUX} = 3.3V		3.15	3.3	3.45	V
V _{CCO} ⁽⁶⁾⁽⁷⁾⁽⁸⁾	Output supply voltage relative to GND			1.1	–	3.45	V
V _{IN}	Input voltage relative to GND	All I/O standards (except PCI)	Commercial temperature (C)	–0.5	–	4.0	V
			Industrial temperature (I)	–0.5	–	3.95	V
			Expanded (Q) temperature	–0.5	–	3.95	V
		PCI I/O standard ⁽⁹⁾		–0.5	–	V _{CCO} + 0.5	V
I _{IN} ⁽¹⁰⁾	Maximum current through pin using PCI I/O standard when forward biasing the clamp diode. ⁽⁹⁾	Commercial (C) and Industrial temperature (I)		–	–	10	mA
		Expanded (Q) temperature		–	–	7	mA
V _{BATT} ⁽¹¹⁾	Battery voltage relative to GND, T _j = 0°C to +85°C (LX75, LX75T, LX100, LX100T, LX150, and LX150T only)			1.0	–	3.6	V
T _j	Junction temperature operating range	Commercial (C) range		0	–	85	°C
		Industrial temperature (I) range		–40	–	100	°C
		Expanded (Q) temperature range		–40	–	125	°C

Notes:

- All voltages are relative to ground.
- See *Interface Performances for Memory Interfaces* in Table 25. The extended performance range is specified for designs not using the standard V_{CCINT} voltage range. The standard V_{CCINT} voltage range is used for:
 - Designs that do not use an MCB
 - LX4 devices
 - Devices in the TQG144 or CPG196 packages
 - Devices with the -3N speed grade
- Recommended maximum voltage droop for V_{CCAUX} is 10 mV/ms.
- During configuration, if V_{CCO_2} is 1.8V, then V_{CCAUX} must be 2.5V.
- The -1L devices require $V_{CCAUX} = 2.5V$ when using the LVDS_25, LVDS_33, BLVDS_25, LVPECL_25, RSDS_25, RSDS_33, PPDS_25, and PPDS_33 I/O standards on inputs. LVPECL_33 is not supported in the -1L devices.
- Configuration data is retained even if V_{CCO} drops to 0V.
- Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
- For PCI systems, the transmitter and receiver should have common supplies for V_{CCO} .
- Devices with a -1L speed grade do not support Xilinx PCI IP.
- Do not exceed a total of 100 mA per bank.
- V_{BATT} is required to maintain the battery backed RAM (BBR) AES key when V_{CCAUX} is not applied. Once V_{CCAUX} is applied, V_{BATT} can be unconnected. When BBR is not used, Xilinx recommends connecting to V_{CCAUX} or GND. However, V_{BATT} can be unconnected.

Table 3: eFUSE Programming Conditions⁽¹⁾

Symbol	Description	Min	Typ	Max	Units
$V_{FS}^{(2)}$	External voltage supply	3.2	3.3	3.4	V
I_{FS}	V_{FS} supply current	–	–	40	mA
V_{CCAUX}	Auxiliary supply voltage relative to GND	3.2	3.3	3.45	V
$R_{FUSE}^{(3)}$	External resistor from R_{FUSE} pin to GND	1129	1140	1151	Ω
V_{CCINT}	Internal supply voltage relative to GND	1.14	1.2	1.26	V
t_j	Temperature range	15	–	85	$^{\circ}\text{C}$

Notes:

1. These specifications apply during programming of the eFUSE AES key. Programming is only supported through JTAG. The AES key is only supported in the following devices: LX75, LX75T, LX100, LX100T, LX150, and LX150T.
2. When programming eFUSE, V_{FS} must be less than or equal to V_{CCAUX} . When not programming or when eFUSE is not used, Xilinx recommends connecting V_{FS} to GND. However, V_{FS} can be between GND and 3.45 V.
3. An R_{FUSE} resistor is required when programming the eFUSE AES key. When not programming or when eFUSE is not used, Xilinx recommends connecting the R_{FUSE} pin to V_{CCAUX} or GND. However, R_{FUSE} can be unconnected.

Table 17: GTP Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	200	800	2000	mV
R_{IN}	Differential input resistance	80	100	120	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTP Transceiver Switching Characteristics

Consult [UG386](#): *Spartan-6 FPGA GTP Transceivers User Guide* for further information.

Table 18: GTP Transceiver Performance

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
F_{GTPMAX}	Maximum GTP transceiver data rate	3.2	3.2	2.7	N/A	Gb/s
$F_{GTPRANGE1}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 1	1.88 to 3.2	1.88 to 3.2	1.88 to 2.7	N/A	Gb/s
$F_{GTPRANGE2}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 2	0.94 to 1.62	0.94 to 1.62	0.94 to 1.62	N/A	Gb/s
$F_{GTPRANGE3}$	GTP transceiver data rate range when PLL_TXDIVSEL_OUT = 4	0.6 to 0.81	0.6 to 0.81	0.6 to 0.81	N/A	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	1.62	1.62	1.62	N/A	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	0.94	0.94	0.94	N/A	GHz

Table 19: GTP Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
$F_{GTPDRCLK}$	GTP transceiver DCLK (DRP clock) maximum frequency	125	125	100	N/A	MHz

Table 20: GTP Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All LXT Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range		60	–	160	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	–	200	–	ps
T_{FCLK}	Reference clock fall time	80% – 20%	–	200	–	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	45	50	55	%
T_{LOCK}	Clock recovery frequency acquisition time	Initial PLL lock	–	–	1	ms
T_{PHASE}	Clock recovery phase acquisition time	Lock to data after PLL has locked to the reference clock	–	–	200	μ s

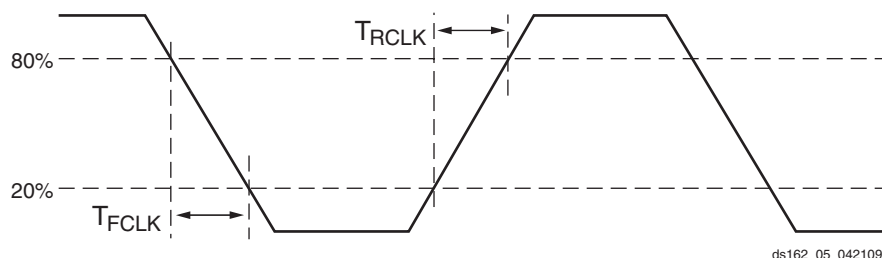


Figure 3: Reference Clock Timing Parameters

Table 23: GTP Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units	
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		–	75	–	ns	
R _{XOVBVDPP}	OOB detect threshold peak-to-peak		60	–	150	mV	
R _{XSST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	–5000	–	0	ppm	
R _{XRL}	Run length (CID)	Internal AC capacitor bypassed	–	–	150	UI	
R _{XPMTOL}	Data/REFCLK PPM offset tolerance	CDR 2 nd -order loop disabled	–200	–	200	ppm	
		CDR 2 nd -order loop enabled	PLL_RXDIVSEL_OUT = 1	–2000	–	2000	ppm
			PLL_RXDIVSEL_OUT = 2	–2000	–	2000	ppm
			PLL_RXDIVSEL_OUT = 4	–1000	–	1000	ppm
SJ Jitter Tolerance ⁽²⁾							
JT_SJ _{3.125}	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s	0.4	–	–	UI	
JT_SJ _{2.5}	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s	0.4	–	–	UI	
JT_SJ _{1.62}	Sinusoidal Jitter ⁽³⁾	1.62 Gb/s	0.5	–	–	UI	
JT_SJ _{1.25}	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s	0.5	–	–	UI	
JT_SJ ₆₁₄	Sinusoidal Jitter ⁽³⁾	614 Mb/s	0.5	–	–	UI	
SJ Jitter Tolerance with Stressed Eye ⁽²⁾⁽⁵⁾							
JT_TJSE _{3.125}	Total Jitter with stressed eye ⁽⁴⁾	3.125 Gb/s	0.65	–	–	UI	
JT_SJSE _{3.125}	Sinusoidal Jitter with stressed eye	3.125 Gb/s	0.1	–	–	UI	
JT_TJSE _{2.7}	Total Jitter with stressed eye ⁽⁴⁾	2.7 Gb/s	0.65	–	–	UI	
JT_SJSE _{2.7}	Sinusoidal Jitter with stressed eye	2.7 Gb/s	0.1	–	–	UI	

Notes:

- Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
- All jitter values are based on a Bit Error Ratio of 1e⁻¹².
- Using 80 MHz sinusoidal jitter only in the absence of deterministic and random jitter.
- Composed of 0.37 UI DJ in the form of ISI and 0.18 UI RJ.
- Measured using PRBS7 data pattern.

Endpoint Block for PCI Express Designs Switching Characteristics

The Endpoint block for PCI Express is available in the Spartan-6 LXT devices. Consult the [Spartan-6 FPGA Integrated Endpoint Block for PCI Express](#) for further information.

Table 24: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
F _{PCIEUSER}	User clock maximum frequency	62.5	62.5	62.5	N/A	MHz

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases. [Table 27](#) lists the production released Spartan-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE® software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 27: Spartan-6 Device Production Software and Speed Specification Release⁽¹⁾

Device	Speed Grade Designations ⁽²⁾			
	-3 ⁽³⁾	-3N	-2 ⁽⁴⁾	-1L
XC6SLX4	ISE 12.4 v1.15	N/A	ISE 12.3 v1.12 ⁽⁵⁾	ISE 13.2 v1.07
XC6SLX9	ISE 12.4 v1.15	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.3 v1.12 ⁽⁵⁾	ISE 13.2 v1.07
XC6SLX16	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 11.5 v1.06	ISE 13.2 v1.07
XC6SLX25	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.2 v1.07
XC6SLX25T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX45	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 11.5 v1.07	ISE 13.1 v1.06
XC6SLX45T	ISE 12.1 v1.08	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.1 v1.08	N/A
XC6SLX75	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.2 v1.07
XC6SLX75T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX100	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 v1.06
XC6SLX100T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XC6SLX150	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 v1.06
XC6SLX150T	ISE 12.2 v1.11 ⁽⁶⁾	ISE 13.1 Update v1.18 ⁽⁷⁾	ISE 12.2 v1.11 ⁽⁶⁾	N/A
XA6SLX4	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX9	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX16	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX25T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX45T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX75T	ISE 13.2 v1.19	N/A	ISE 13.2 v1.19	N/A
XA6SLX100	N/A	N/A	ISE 13.3 v1.20	N/A

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVC MOS33, Fast, 8 mA	1.34	1.46	1.59	1.82	2.07	2.21	2.41	3.03	2.07	2.21	2.41	3.03	ns
LVC MOS33, Fast, 12 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVC MOS33, Fast, 16 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVC MOS33, Fast, 24 mA	1.34	1.46	1.59	1.82	1.65	1.79	1.99	2.62	1.65	1.79	1.99	2.62	ns
LVC MOS25, QUIETIO, 2 mA	0.82	0.94	1.07	1.31	4.81	4.95	5.15	5.79	4.81	4.95	5.15	5.79	ns
LVC MOS25, QUIETIO, 4 mA	0.82	0.94	1.07	1.31	3.70	3.84	4.04	4.66	3.70	3.84	4.04	4.66	ns
LVC MOS25, QUIETIO, 6 mA	0.82	0.94	1.07	1.31	3.46	3.60	3.80	4.38	3.46	3.60	3.80	4.38	ns
LVC MOS25, QUIETIO, 8 mA	0.82	0.94	1.07	1.31	3.20	3.34	3.54	4.12	3.20	3.34	3.54	4.12	ns
LVC MOS25, QUIETIO, 12 mA	0.82	0.94	1.07	1.31	2.83	2.97	3.17	3.75	2.83	2.97	3.17	3.75	ns
LVC MOS25, QUIETIO, 16 mA	0.82	0.94	1.07	1.31	2.64	2.78	2.98	3.64	2.64	2.78	2.98	3.64	ns
LVC MOS25, QUIETIO, 24 mA	0.82	0.94	1.07	1.31	2.45	2.59	2.79	3.42	2.45	2.59	2.79	3.42	ns
LVC MOS25, Slow, 2 mA	0.82	0.94	1.07	1.31	3.78	3.92	4.12	4.76	3.78	3.92	4.12	4.76	ns
LVC MOS25, Slow, 4 mA	0.82	0.94	1.07	1.31	2.79	2.93	3.13	3.73	2.79	2.93	3.13	3.73	ns
LVC MOS25, Slow, 6 mA	0.82	0.94	1.07	1.31	2.73	2.87	3.07	3.66	2.73	2.87	3.07	3.66	ns
LVC MOS25, Slow, 8 mA	0.82	0.94	1.07	1.31	2.48	2.62	2.82	3.42	2.48	2.62	2.82	3.42	ns
LVC MOS25, Slow, 12 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns
LVC MOS25, Slow, 16 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.95	2.01	2.15	2.35	2.95	ns
LVC MOS25, Slow, 24 mA	0.82	0.94	1.07	1.31	2.01	2.15	2.35	2.94	2.01	2.15	2.35	2.94	ns
LVC MOS25, Fast, 2 mA	0.82	0.94	1.07	1.31	3.35	3.49	3.69	4.31	3.35	3.49	3.69	4.31	ns
LVC MOS25, Fast, 4 mA	0.82	0.94	1.07	1.31	2.25	2.39	2.59	3.22	2.25	2.39	2.59	3.22	ns
LVC MOS25, Fast, 6 mA	0.82	0.94	1.07	1.31	2.09	2.23	2.43	3.05	2.09	2.23	2.43	3.05	ns
LVC MOS25, Fast, 8 mA	0.82	0.94	1.07	1.31	2.02	2.16	2.36	2.98	2.02	2.16	2.36	2.98	ns
LVC MOS25, Fast, 12 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVC MOS25, Fast, 16 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVC MOS25, Fast, 24 mA	0.82	0.94	1.07	1.31	1.56	1.70	1.90	2.52	1.56	1.70	1.90	2.52	ns
LVC MOS18, QUIETIO, 2 mA	1.18	1.30	1.43	2.04	5.92	6.06	6.26	6.80	5.92	6.06	6.26	6.80	ns
LVC MOS18, QUIETIO, 4 mA	1.18	1.30	1.43	2.04	4.74	4.88	5.08	5.63	4.74	4.88	5.08	5.63	ns
LVC MOS18, QUIETIO, 6 mA	1.18	1.30	1.43	2.04	4.05	4.19	4.39	4.96	4.05	4.19	4.39	4.96	ns
LVC MOS18, QUIETIO, 8 mA	1.18	1.30	1.43	2.04	3.71	3.85	4.05	4.63	3.71	3.85	4.05	4.63	ns
LVC MOS18, QUIETIO, 12 mA	1.18	1.30	1.43	2.04	3.35	3.49	3.69	4.27	3.35	3.49	3.69	4.27	ns
LVC MOS18, QUIETIO, 16 mA	1.18	1.30	1.43	2.04	3.20	3.34	3.54	4.14	3.20	3.34	3.54	4.14	ns
LVC MOS18, QUIETIO, 24 mA	1.18	1.30	1.43	2.04	2.96	3.10	3.30	3.98	2.96	3.10	3.30	3.98	ns
LVC MOS18, Slow, 2 mA	1.18	1.30	1.43	2.04	4.62	4.76	4.96	5.54	4.62	4.76	4.96	5.54	ns
LVC MOS18, Slow, 4 mA	1.18	1.30	1.43	2.04	3.69	3.83	4.03	4.60	3.69	3.83	4.03	4.60	ns
LVC MOS18, Slow, 6 mA	1.18	1.30	1.43	2.04	3.00	3.14	3.34	3.94	3.00	3.14	3.34	3.94	ns
LVC MOS18, Slow, 8 mA	1.18	1.30	1.43	2.04	2.19	2.33	2.53	3.17	2.19	2.33	2.53	3.17	ns
LVC MOS18, Slow, 12 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns
LVC MOS18, Slow, 16 mA	1.18	1.30	1.43	2.04	1.99	2.13	2.33	2.95	1.99	2.13	2.33	2.95	ns

Table 28: IOB Switching Characteristics for the Commercial (XC) Spartan-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	-3	-3N	-2	-1L ⁽¹⁾	
LVC MOS12, Fast, 2 mA	0.91	1.03	1.16	1.51	3.46	3.60	3.80	4.44	3.46	3.60	3.80	4.44	ns
LVC MOS12, Fast, 4 mA	0.91	1.03	1.16	1.51	2.35	2.49	2.69	3.30	2.35	2.49	2.69	3.30	ns
LVC MOS12, Fast, 6 mA	0.91	1.03	1.16	1.51	1.79	1.93	2.13	2.75	1.79	1.93	2.13	2.75	ns
LVC MOS12, Fast, 8 mA	0.91	1.03	1.16	1.51	1.68	1.82	2.02	2.64	1.68	1.82	2.02	2.64	ns
LVC MOS12, Fast, 12 mA	0.91	1.03	1.16	1.51	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns
LVC MOS12_JEDEC, QUIETIO, 2 mA	1.50	1.62	1.75	1.88	6.39	6.53	6.73	7.31	6.39	6.53	6.73	7.31	ns
LVC MOS12_JEDEC, QUIETIO, 4 mA	1.50	1.62	1.75	1.88	4.98	5.12	5.32	5.88	4.98	5.12	5.32	5.88	ns
LVC MOS12_JEDEC, QUIETIO, 6 mA	1.50	1.62	1.75	1.88	4.67	4.81	5.01	5.54	4.67	4.81	5.01	5.54	ns
LVC MOS12_JEDEC, QUIETIO, 8 mA	1.50	1.62	1.75	1.88	4.23	4.37	4.57	5.22	4.23	4.37	4.57	5.22	ns
LVC MOS12_JEDEC, QUIETIO, 12 mA	1.50	1.62	1.75	1.88	3.99	4.13	4.33	4.94	3.99	4.13	4.33	4.94	ns
LVC MOS12_JEDEC, Slow, 2 mA	1.50	1.62	1.75	1.88	5.00	5.14	5.34	5.90	5.00	5.14	5.34	5.90	ns
LVC MOS12_JEDEC, Slow, 4 mA	1.50	1.62	1.75	1.88	2.85	2.99	3.19	3.80	2.85	2.99	3.19	3.80	ns
LVC MOS12_JEDEC, Slow, 6 mA	1.50	1.62	1.75	1.88	2.76	2.90	3.10	3.72	2.76	2.90	3.10	3.72	ns
LVC MOS12_JEDEC, Slow, 8 mA	1.50	1.62	1.75	1.88	2.35	2.49	2.69	3.30	2.35	2.49	2.69	3.30	ns
LVC MOS12_JEDEC, Slow, 12 mA	1.50	1.62	1.75	1.88	2.09	2.23	2.43	3.05	2.09	2.23	2.43	3.05	ns
LVC MOS12_JEDEC, Fast, 2 mA	1.50	1.62	1.75	1.88	3.46	3.60	3.80	4.42	3.46	3.60	3.80	4.42	ns
LVC MOS12_JEDEC, Fast, 4 mA	1.50	1.62	1.75	1.88	2.35	2.49	2.69	3.31	2.35	2.49	2.69	3.31	ns
LVC MOS12_JEDEC, Fast, 6 mA	1.50	1.62	1.75	1.88	1.79	1.93	2.13	2.76	1.79	1.93	2.13	2.76	ns
LVC MOS12_JEDEC, Fast, 8 mA	1.50	1.62	1.75	1.88	1.69	1.83	2.03	2.65	1.69	1.83	2.03	2.65	ns
LVC MOS12_JEDEC, Fast, 12 mA	1.50	1.62	1.75	1.88	1.66	1.80	2.00	2.62	1.66	1.80	2.00	2.62	ns

Notes:

1. The -1L values listed in this table are also applicable to the Spartan-6Q devices.
2. Devices with a -1L speed grade do not support Xilinx PCI IP.

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVC MOS33, Slow, 6 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns
LVC MOS33, Slow, 8 mA	1.41	1.59	2.79	2.99	2.79	2.99	ns
LVC MOS33, Slow, 12 mA	1.41	1.59	2.53	2.73	2.53	2.73	ns
LVC MOS33, Slow, 16 mA	1.41	1.59	2.45	2.65	2.45	2.65	ns
LVC MOS33, Slow, 24 mA	1.41	1.59	2.42	2.62	2.42	2.62	ns
LVC MOS33, Fast, 2 mA	1.41	1.59	4.05	4.25	4.05	4.25	ns
LVC MOS33, Fast, 4 mA	1.41	1.59	2.66	2.86	2.66	2.86	ns
LVC MOS33, Fast, 6 mA	1.41	1.59	2.46	2.66	2.46	2.66	ns
LVC MOS33, Fast, 8 mA	1.41	1.59	2.21	2.41	2.21	2.41	ns
LVC MOS33, Fast, 12 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns
LVC MOS33, Fast, 16 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns
LVC MOS33, Fast, 24 mA	1.41	1.59	1.80	2.00	1.80	2.00	ns
LVC MOS25, QUIETIO, 2 mA	0.89	1.07	5.00	5.20	5.00	5.20	ns
LVC MOS25, QUIETIO, 4 mA	0.89	1.07	3.85	4.05	3.85	4.05	ns
LVC MOS25, QUIETIO, 6 mA	0.89	1.07	3.60	3.80	3.60	3.80	ns
LVC MOS25, QUIETIO, 8 mA	0.89	1.07	3.34	3.54	3.34	3.54	ns
LVC MOS25, QUIETIO, 12 mA	0.89	1.07	2.98	3.18	2.98	3.18	ns
LVC MOS25, QUIETIO, 16 mA	0.89	1.07	2.79	2.99	2.79	2.99	ns
LVC MOS25, QUIETIO, 24 mA	0.89	1.07	2.64	2.84	2.64	2.84	ns
LVC MOS25, Slow, 2 mA	0.89	1.07	3.96	4.16	3.96	4.16	ns
LVC MOS25, Slow, 4 mA	0.89	1.07	2.96	3.16	2.96	3.16	ns
LVC MOS25, Slow, 6 mA	0.89	1.07	2.88	3.08	2.88	3.08	ns
LVC MOS25, Slow, 8 mA	0.89	1.07	2.63	2.83	2.63	2.83	ns
LVC MOS25, Slow, 12 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns
LVC MOS25, Slow, 16 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns
LVC MOS25, Slow, 24 mA	0.89	1.07	2.15	2.35	2.15	2.35	ns
LVC MOS25, Fast, 2 mA	0.89	1.07	3.52	3.72	3.52	3.72	ns
LVC MOS25, Fast, 4 mA	0.89	1.07	2.43	2.63	2.43	2.63	ns
LVC MOS25, Fast, 6 mA	0.89	1.07	2.23	2.43	2.23	2.43	ns
LVC MOS25, Fast, 8 mA	0.89	1.07	2.16	2.36	2.16	2.36	ns
LVC MOS25, Fast, 12 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns
LVC MOS25, Fast, 16 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns
LVC MOS25, Fast, 24 mA	0.89	1.07	1.70	1.90	1.70	1.90	ns
LVC MOS18, QUIETIO, 2 mA	1.25	1.43	6.11	6.31	6.11	6.31	ns
LVC MOS18, QUIETIO, 4 mA	1.25	1.43	4.88	5.08	4.88	5.08	ns
LVC MOS18, QUIETIO, 6 mA	1.25	1.43	4.20	4.40	4.20	4.40	ns
LVC MOS18, QUIETIO, 8 mA	1.25	1.43	3.86	4.06	3.86	4.06	ns
LVC MOS18, QUIETIO, 12 mA	1.25	1.43	3.49	3.69	3.49	3.69	ns

Table 29: IOB Switching Characteristics for the Automotive XA Spartan-6 and the Spartan-6Q Devices⁽¹⁾ (Cont'd)

I/O Standard	T _{IOPI}		T _{IOOP}		T _{IOTP}		Units
	Speed Grade		Speed Grade		Speed Grade		
	-3	-2	-3	-2	-3	-2	
LVC MOS18, QUIETIO, 16 mA	1.25	1.43	3.34	3.54	3.34	3.54	ns
LVC MOS18, QUIETIO, 24 mA	1.25	1.43	3.18	3.38	3.18	3.38	ns
LVC MOS18, Slow, 2 mA	1.25	1.43	4.79	4.99	4.79	4.99	ns
LVC MOS18, Slow, 4 mA	1.25	1.43	3.84	4.04	3.84	4.04	ns
LVC MOS18, Slow, 6 mA	1.25	1.43	3.17	3.37	3.17	3.37	ns
LVC MOS18, Slow, 8 mA	1.25	1.43	2.37	2.57	2.37	2.57	ns
LVC MOS18, Slow, 12 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVC MOS18, Slow, 16 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVC MOS18, Slow, 24 mA	1.25	1.43	2.13	2.33	2.13	2.33	ns
LVC MOS18, Fast, 2 mA	1.25	1.43	3.78	3.98	3.78	3.98	ns
LVC MOS18, Fast, 4 mA	1.25	1.43	2.54	2.74	2.54	2.74	ns
LVC MOS18, Fast, 6 mA	1.25	1.43	2.02	2.22	2.02	2.22	ns
LVC MOS18, Fast, 8 mA	1.25	1.43	1.95	2.15	1.95	2.15	ns
LVC MOS18, Fast, 12 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVC MOS18, Fast, 16 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVC MOS18, Fast, 24 mA	1.25	1.43	1.85	2.05	1.85	2.05	ns
LVC MOS18_JEDEC, QUIETIO, 2 mA	1.01	1.19	6.09	6.29	6.09	6.29	ns
LVC MOS18_JEDEC, QUIETIO, 4 mA	1.01	1.19	4.89	5.09	4.89	5.09	ns
LVC MOS18_JEDEC, QUIETIO, 6 mA	1.01	1.19	4.20	4.40	4.20	4.40	ns
LVC MOS18_JEDEC, QUIETIO, 8 mA	1.01	1.19	3.87	4.07	3.87	4.07	ns
LVC MOS18_JEDEC, QUIETIO, 12 mA	1.01	1.19	3.49	3.69	3.49	3.69	ns
LVC MOS18_JEDEC, QUIETIO, 16 mA	1.01	1.19	3.34	3.54	3.34	3.54	ns
LVC MOS18_JEDEC, QUIETIO, 24 mA	1.01	1.19	3.17	3.37	3.17	3.37	ns
LVC MOS18_JEDEC, Slow, 2 mA	1.01	1.19	4.79	4.99	4.79	4.99	ns
LVC MOS18_JEDEC, Slow, 4 mA	1.01	1.19	3.84	4.04	3.84	4.04	ns
LVC MOS18_JEDEC, Slow, 6 mA	1.01	1.19	3.18	3.38	3.18	3.38	ns
LVC MOS18_JEDEC, Slow, 8 mA	1.01	1.19	2.37	2.57	2.37	2.57	ns
LVC MOS18_JEDEC, Slow, 12 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVC MOS18_JEDEC, Slow, 16 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVC MOS18_JEDEC, Slow, 24 mA	1.01	1.19	2.13	2.33	2.13	2.33	ns
LVC MOS18_JEDEC, Fast, 2 mA	1.01	1.19	3.75	3.95	3.75	3.95	ns
LVC MOS18_JEDEC, Fast, 4 mA	1.01	1.19	2.54	2.74	2.54	2.74	ns
LVC MOS18_JEDEC, Fast, 6 mA	1.01	1.19	2.02	2.22	2.02	2.22	ns
LVC MOS18_JEDEC, Fast, 8 mA	1.01	1.19	1.94	2.14	1.94	2.14	ns
LVC MOS18_JEDEC, Fast, 12 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns
LVC MOS18_JEDEC, Fast, 16 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns
LVC MOS18_JEDEC, Fast, 24 mA	1.01	1.19	1.86	2.06	1.86	2.06	ns

Table 34: SSO Limit per V_{CCO}/GND Pair

V_{CCO}	I/O Standard	Drive	Slew	SSO Limit per V_{CCO}/GND Pair			
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324	
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5
1.2V	LVCMOS12, LVCMOS12_JEDEC	2	Fast	30 ⁽¹⁾	35	30	35
			Slow	51	55	51	52
			QuietIO	71	58	71	70
		4	Fast	17	17	17	19
			Slow	23	25	23	22
			QuietIO	35	32	35	32
		6	Fast	13	15	13	14
			Slow	19	20	19	17
			QuietIO	26	24	26	24
		8	Fast	N/A	12	N/A	12
			Slow	N/A	15	N/A	13
			QuietIO	N/A	20	N/A	19
		12	Fast	N/A	5	N/A	4
			Slow	N/A	8	N/A	5
			QuietIO	N/A	11	N/A	10

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V _{CCO}	I/O Standard	Drive	Slew	SSO Limit per V _{CCO} /GND Pair				
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324		
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5	
1.8V	LVCMOS18, LVCMOS18_JEDEC	2	Fast	39	46	39	47	
			Slow	65	75	65	74	
			QuietIO	80	80	80	85	
		4	Fast	22	25	22	25	
			Slow	38	36	38	29	
			QuietIO	45	40	45	35	
		6	Fast	16	18	16	17	
			Slow	27	25	27	19	
			QuietIO	30	28	30	23	
		8	Fast	13	15	13	14	
			Slow	16	18	16	16	
			QuietIO	25	22	25	18	
		12	Fast	5	7	5	5	
			Slow	7	8	7	6	
			QuietIO	11	10	11	8	
		16	Fast	4	5	4	4	
			Slow	7	8	7	5	
			QuietIO	11	10	11	8	
		24	Fast	N/A	5	N/A	3	
			Slow	N/A	8	N/A	8	
			QuietIO	N/A	10	N/A	8	
	HSTL_I_18				9	10	9	9
	HSTL_II_18				N/A	5	N/A	6
	HSTL_III_18				9	10	9	11
	DIFF_HSTL_I_18				27	30	27	27
	DIFF_HSTL_II_18				N/A	15	N/A	18
	DIFF_HSTL_III_18				27	30	27	33
MOBILE_DDR ⁽³⁾				12	14	12	14	
DIFF_MOBILE_DDR ⁽³⁾				36	42	36	42	
SSTL_18_I ⁽³⁾				9	10	9	10	
SSTL_18_II ⁽³⁾				N/A	5	N/A	4	
DIFF_SSTL_18_I ⁽³⁾				27	30	27	30	
DIFF_SSTL_18_II ⁽³⁾				N/A	15	N/A	12	

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V _{CCO}	I/O Standard	Drive	Slew	SSO Limit per V _{CCO} /GND Pair					
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324			
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5		
2.5V	LVCMOS25	2	Fast	38	43	38	43		
			Slow	46	52	46	48		
			QuietIO	57	64	57	59		
		4	Fast	21	24	21	23		
			Slow	26	31	26	27		
			QuietIO	33	32	33	30		
		6	Fast	15	17	15	16		
			Slow	19	22	19	19		
			QuietIO	25	23	25	19		
		8	Fast	12	15	12	14		
			Slow	15	18	15	16		
			QuietIO	21	19	21	16		
		12	Fast	1	3	1	1		
			Slow	2	7	2	4		
			QuietIO	3	8	3	8		
		16	Fast	1	3	1	1		
			Slow	3	7	3	3		
			QuietIO	4	9	4	8		
		24	Fast	N/A	3	N/A	1		
			Slow	N/A	5	N/A	2		
			QuietIO	N/A	8	N/A	6		
		SSTL_2_I ⁽³⁾				10	11	10	11
		SSTL_2_II ⁽³⁾				N/A	7	N/A	7
		DIFF_SSTL_2_I ⁽³⁾				30	33	30	33
	DIFF_SSTL_2_II ⁽³⁾				N/A	21	N/A	24	

Table 34: SSO Limit per V_{CCO}/GND Pair (Cont'd)

V _{CCO}	I/O Standard	Drive	Slew	SSO Limit per V _{CCO} /GND Pair				
				All TQG144, CPG196, CSG225, FT(G)256, and LX devices in CSG324		All CS(G)484, FG(G)484, FG(G)676, FG(G)900, and LXT devices in CSG324		
				Bank 0/2	Bank 1/3	Bank 0/2	Bank 1/3/4/5	
3.3V	LVTTTL	2	Fast	53	65	53	62	
			Slow	70	80	70	73	
			QuietIO	79	89	79	91	
		4	Fast	23	30	23	27	
			Slow	34	41	34	37	
			QuietIO	44	49	44	46	
		6	Fast	16	21	16	20	
			Slow	21	28	21	25	
			QuietIO	34	39	34	34	
		8	Fast	12	16	12	15	
			Slow	16	22	16	19	
			QuietIO	27	28	27	24	
		12	Fast	1	3	1	1	
			Slow	2	5	2	4	
			QuietIO	2	10	2	8	
		16	Fast	1	3	1	1	
			Slow	1	7	1	2	
			QuietIO	3	11	3	8	
		24	Fast	1	2	1	1	
			Slow	2	5	2	2	
			QuietIO	8	9	8	8	
	PCI33_3				18	19	18	19
	PCI66_3				18	19	18	19
	SSTL_3_I				5	8	5	8
	SSTL_3_II				3	5	3	3
	DIFF_SSTL_3_I				15	24	15	24
	DIFF_SSTL_3_II				9	15	9	9
	SDIO				17	18	17	15

Input Serializer/Deserializer Switching Characteristics

Table 37: ISERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold for Control Lines						
T _{ISCKC_BITSIP} / T _{ISCKC_BITSIP}	BITSIP pin Setup/Hold with respect to CLKDIV	0.16/ −0.09	0.20/ −0.09	0.31/ −0.09	0.34/ −0.14	ns
T _{ISCKC_CE} / T _{ISCKC_CE}	CE pin Setup/Hold with respect to CLK	0.71/ −0.47	0.71/ −0.42	0.97/ −0.42	1.39/ −0.71	ns
Setup/Hold for Data Lines						
T _{ISDCK_D} / T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.24/ −0.15	0.25/ −0.05	0.29/ −0.05	0.09/ −0.05	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY2)	−0.25/ 0.30	−0.25/ 0.42	−0.25/ 0.56	−0.54/ 0.67	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	−0.03/ 0.04	−0.03/ 0.16	−0.03/ 0.18	−0.05/ 0.12	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY2)	−0.40/ 0.48	−0.40/ 0.53	−0.40/ 0.71	−0.71/ 0.86	ns
Sequential Delays						
T _{ISCKO_Q}	CLKDIV to out at Q pin	1.30	1.44	2.02	2.22	ns
F _{CLKDIV}	CLKDIV maximum frequency	270	262.5	250	125	MHz

Output Serializer/Deserializer Switching Characteristics

Table 38: OSERDES2 Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-3N	-2	-1L	
Setup/Hold						
T _{OSDCK_D} /T _{OSCKD_D}	D input Setup/Hold with respect to CLKDIV	−0.03/ 1.02	−0.03/ 1.17	−0.03/ 1.27	−0.02/ 0.23	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input Setup/Hold with respect to CLK	−0.05/ 1.03	−0.05/ 1.13	−0.05/ 1.23	−0.05/ 0.24	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input Setup/Hold with respect to CLK	0.12/ −0.03	0.15/ −0.03	0.24/ −0.03	0.28/ −0.17	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input Setup/Hold with respect to CLK	0.14/ −0.08	0.17/ −0.08	0.27/ −0.08	0.31/ −0.16	ns
Sequential Delays						
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.94	1.11	1.51	1.89	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.94	1.11	1.51	1.91	ns
F _{CLKDIV}	CLKDIV maximum frequency	270	262.5	250	125	MHz

Notes:

1. $T_{OSDCK_T2} / T_{OSCKD_T2}$ (T input setup/hold with respect to CLKDIV) are reported as $T_{OSDCK_T} / T_{OSCKD_T}$ in TRACE report.

Table 52: PLL Specification (Cont'd)

Symbol	Description	Device ⁽¹⁾	Speed Grade				Units
			-3	-3N	-2	-1L	
F _{INMIN}	Minimum Input Clock Frequency	LX devices	19	19	19	19	MHz
		LXT devices	19	19	19	N/A	MHz
F _{INJITTER}	Maximum Input Clock Period Jitter: 19–200 MHz	All	1 ns Maximum				
	Maximum Input Clock Period Jitter: > 200 MHz	All	<20% of clock input period Maximum				
F _{INDUTY}	Allowable Input Duty Cycle: 19—199 MHz	All	25/75				%
	Allowable Input Duty Cycle: 200—299 MHz	All	35/65				%
	Allowable Input Duty Cycle: > 300 MHz	All	45/55				%
F _{VCOMIN}	Minimum PLL VCO Frequency	LX devices	400	400	400	400	MHz
		LXT devices	400	400	400	N/A	MHz
F _{VCOMAX}	Maximum PLL VCO Frequency	LX devices	1080	1050	1000	1000	MHz
		LXT devices	1080	1050	1000	N/A	MHz
F _{BANDWIDTH}	Low PLL Bandwidth at Typical ⁽³⁾	All	1	1	1	1	MHz
	High PLL Bandwidth at Typical ⁽³⁾	All	4	4	4	4	MHz
T _{STAPHAOFFSET}	Static Phase Offset of the PLL Outputs	All	0.12	0.12	0.12	0.15	ns
T _{OUTJITTER}	PLL Output Jitter ⁽³⁾	All	Note 2				
T _{OUTDUTY}	PLL Output Clock Duty Cycle Precision ⁽⁴⁾	All	0.15	0.15	0.20	0.25	ns
T _{LOCKMAX}	PLL Maximum Lock Time	All	100	100	100	100	μs
F _{OUTMAX}	PLL Maximum Output Frequency for BUFGMUX	LX devices	400	400	375	250	MHz
		LXT devices	400	400	375	N/A	MHz
	PLL Maximum Output Frequency for BUFPLL	LX devices	1080	1050	950	500	MHz
		LXT devices	1080	1050	950	N/A	MHz
F _{OUTMIN}	PLL Minimum Output Frequency ⁽⁵⁾	All	3.125	3.125	3.125	3.125	MHz
T _{EXTFDVAR}	External Clock Feedback Variation: 19–200 MHz	All	1 ns Maximum				
	External Clock Feedback Variation: > 200 MHz	All	< 20% of clock input period Maximum				
RST _{MINPULSE}	Minimum Reset Pulse Width	All	5	5	5	5	ns
F _{PFDMAX} ⁽⁵⁾	Maximum Frequency at the Phase Frequency Detector	LX devices	500	500	400	300	MHz
		LXT devices	500	500	400	N/A	MHz
F _{PFDMIN}	Minimum Frequency at the Phase Frequency Detector	LX devices	19	19	19	19	MHz
		LXT devices	19	19	19	N/A	MHz
T _{FBDELAY}	Maximum Delay in the Feedback Path	All	3 ns Max or one CLKIN cycle				

Notes:

1. LXT devices are not available with a -1L speed grade.
2. Values for this parameter are available in the Clocking Wizard.
3. The PLL does not filter typical spread spectrum input clocks because they are usually far below the bandwidth filter frequencies.
4. Includes global clock buffer.
5. Calculated as $F_{VCO}/128$ assuming output duty cycle is 50%.
6. When using CLK_FEEDBACK = CLKOUT0 with BUFIO2 feedback, the feedback frequency will be higher than the phase frequency detector frequency. $F_{PFDMAX} = F_{CLKFB} / CLKFBOUT_MULT$

Table 56: Switching Characteristics for the Digital Frequency Synthesizer (DFS) for DCM_SP⁽¹⁾

Symbol	Description	Speed Grade								Units
		-3		-3N		-2		-1L		
		Min	Max	Min	Max	Min	Max	Min	Max	
Output Frequency Ranges										
CLKOUT_FREQ_FX	Frequency for the CLKFX and CLKFX180 outputs	5	375	5	375	5	333	5	200	MHz
Output Clock Jitter ⁽²⁾⁽³⁾										
CLKOUT_PER_JITT_FX	Period jitter at the CLKFX and CLKFX180 outputs. When CLKIN < 20 MHz	Use the Clocking Wizard								ps
	Period jitter at the CLKFX and CLKFX180 outputs. When CLKIN > 20 MHz	Typical = ±(1% of CLKFX period + 100)								ps
Duty Cycle ⁽⁴⁾⁽⁵⁾										
CLKOUT_DUTY_CYCLE_FX	Duty cycle precision for the CLKFX and CLKFX180 outputs including the BUFGMUX and clock tree duty-cycle distortion	Maximum = ±(1% of CLKFX period + 350)								ps
Phase Alignment ⁽⁵⁾										
CLKOUT_PHASE_FX	Phase offset between the DFS CLKFX output and the DLL CLK0 output when both the DFS and DLL are used	–	±200	–	±200	–	±200	–	±250	ps
CLKOUT_PHASE_FX180	Phase offset between the DFS CLKFX180 output and the DLL CLK0 output when both the DFS and DLL are used	Maximum = ±(1% of CLKFX period + 200)								ps
LOCKED Time										
LOCK_FX ⁽²⁾	When FCLKIN < 50 MHz, the time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX and CLKFX180 signals are valid. When using both the DLL and the DFS, use the longer locking time.	–	5	–	5	–	5	–	5	ms
	When FCLKIN > 50 MHz, the time from deassertion at the DCM's reset input to the rising transition at its LOCKED output. The DFS asserts LOCKED when the CLKFX and CLKFX180 signals are valid. When using both the DLL and the DFS, use the longer locking time.	–	0.45	–	0.45	–	0.45	–	0.60	ms

Notes:

- The values in this table are based on the operating conditions described in Table 2 and Table 55.
- For optimal jitter tolerance and a faster LOCK time, use the CLKIN_PERIOD attribute.
- Output jitter is characterized with no input jitter. Output jitter strongly depends on the environment, including the number of SSOs, the output drive strength, CLB utilization, CLB switching activities, switching frequency, power supply, and PCB design. The actual maximum output jitter depends on the system application.
- The CLKFX, CLKFXDV, and CLKFX180 outputs have a duty cycle of approximately 50%.
- Some duty cycle and alignment specifications include a percentage of the CLKFX output period. For example, this data sheet specifies a maximum CLKFX jitter of $\pm(1\%$ of CLKFX period + 200 ps). Assuming that the CLKFX output frequency is 100 MHz, the equivalent CLKFX period is 10 ns, and 1% of 10 ns is 0.1 ns or 100 ps. Accordingly, the maximum jitter is $\pm(100\text{ ps} + 200\text{ ps}) = \pm 300\text{ ps}$.

Spartan-6 Device Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 63 through Table 69. Values are expressed in nanoseconds unless otherwise noted.

Table 63: Global Clock Input to Output Delay Without DCM or PLL

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>without</i> DCM or PLL							
T _{ICKOF}	Global Clock and OUTFF <i>without</i> DCM or PLL	XC6SLX4	6.12	N/A	7.68	9.41	ns
		XC6SLX9	6.12	6.51	7.68	9.41	ns
		XC6SLX16	5.98	6.42	7.48	9.10	ns
		XC6SLX25	6.20	6.69	7.84	9.44	ns
		XC6SLX25T	6.20	6.69	7.84	N/A	ns
		XC6SLX45	6.37	6.88	8.10	9.61	ns
		XC6SLX45T	6.37	6.88	8.10	N/A	ns
		XC6SLX75	6.39	6.99	8.16	10.18	ns
		XC6SLX75T	6.39	6.99	8.16	N/A	ns
		XC6SLX100	6.59	7.18	8.41	10.31	ns
		XC6SLX100T	6.59	7.18	8.41	N/A	ns
		XC6SLX150	6.98	7.68	8.80	10.62	ns
		XC6SLX150T	6.98	7.68	8.80	N/A	ns
		XA6SLX4	6.44	N/A	7.68	N/A	ns
		XA6SLX9	6.44	N/A	7.68	N/A	ns
		XA6SLX16	6.30	N/A	7.48	N/A	ns
		XA6SLX25	6.52	N/A	7.84	N/A	ns
		XA6SLX25T	6.52	N/A	7.84	N/A	ns
		XA6SLX45	6.69	N/A	8.12	N/A	ns
		XA6SLX45T	6.69	N/A	8.12	N/A	ns
		XA6SLX75	6.89	N/A	8.16	N/A	ns
		XA6SLX75T	6.89	N/A	8.16	N/A	ns
		XA6SLX100	N/A	N/A	8.36	N/A	ns
		XQ6SLX75	N/A	N/A	8.16	10.18	ns
		XQ6SLX75T	6.89	N/A	8.16	N/A	ns
		XQ6SLX150	N/A	N/A	8.80	10.62	ns
		XQ6SLX150T	7.61	N/A	8.80	N/A	ns

Notes:

- Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

Table 65: Global Clock Input to Output Delay With DCM in Source-Synchronous Mode

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
LVCMOS25 Global Clock Input to Output Delay using Output Flip-Flop, 12mA, Fast Slew Rate, <i>with</i> DCM in Source-Synchronous Mode.							
T _{ICKOFDCM_0}	Global Clock and OUTFF <i>with</i> DCM	XC6SLX4	5.03	N/A	7.21	8.05	ns
		XC6SLX9	5.03	6.13	7.21	8.05	ns
		XC6SLX16	5.08	5.51	6.44	7.96	ns
		XC6SLX25	4.81	5.13	5.69	7.94	ns
		XC6SLX25T	4.81	5.13	5.69	N/A	ns
		XC6SLX45	5.26	5.69	6.63	7.92	ns
		XC6SLX45T	5.26	5.69	6.63	N/A	ns
		XC6SLX75	4.77	5.18	5.88	7.95	ns
		XC6SLX75T	4.77	5.18	5.88	N/A	ns
		XC6SLX100	4.72	5.11	5.76	8.59	ns
		XC6SLX100T	4.76	5.11	5.76	N/A	ns
		XC6SLX150	4.90	5.30	5.93	7.93	ns
		XC6SLX150T	4.90	5.30	5.93	N/A	ns
		XA6SLX4	5.35	N/A	7.21	N/A	ns
		XA6SLX9	5.35	N/A	7.21	N/A	ns
		XA6SLX16	5.42	N/A	6.44	N/A	ns
		XA6SLX25	5.13	N/A	5.69	N/A	ns
		XA6SLX25T	5.13	N/A	5.79	N/A	ns
		XA6SLX45	5.58	N/A	6.63	N/A	ns
		XA6SLX45T	5.58	N/A	6.63	N/A	ns
		XA6SLX75	5.09	N/A	5.87	N/A	ns
		XA6SLX75T	5.09	N/A	5.87	N/A	ns
		XA6SLX100	N/A	N/A	6.44	N/A	ns
		XQ6SLX75	N/A	N/A	5.87	7.95	ns
		XQ6SLX75T	5.09	N/A	5.87	N/A	ns
		XQ6SLX150	N/A	N/A	6.06	7.93	ns
		XQ6SLX150T	5.50	N/A	6.06	N/A	ns

Notes:

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. DCM output jitter is already included in the timing calculation.

Spartan-6 Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. The representative values for typical pin locations and normal clock loading are listed in Table 70 through Table 77. Values are expressed in nanoseconds unless otherwise noted.

Table 70: Global Clock Setup and Hold Without DCM or PLL (No Delay)

Symbol	Description	Device	Speed Grade				Units
			-3	-3N	-2	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVC MOS25 Standard.(1)							
T _{PSND} / T _{PHND}	No Delay Global Clock and IFF(3) without DCM or PLL	XC6SLX4	0.10/1.56	N/A	0.10/1.83	0.07/2.54	ns
		XC6SLX9	0.10/1.56	0.10/1.57	0.10/1.84	0.07/2.54	ns
		XC6SLX16	0.12/1.42	0.12/1.48	0.12/1.64	0.13/2.19	ns
		XC6SLX25	0.18/1.64	0.18/1.75	0.18/1.99	0.11/2.57	ns
		XC6SLX25T	0.18/1.64	0.18/1.75	0.18/1.99	N/A	ns
		XC6SLX45	−0.08/1.80	−0.08/1.95	−0.08/2.27	−0.17/2.74	ns
		XC6SLX45T	−0.08/1.80	−0.08/1.95	−0.08/2.27	N/A	ns
		XC6SLX75	0.13/1.81	0.13/2.06	0.13/2.27	−0.12/3.30	ns
		XC6SLX75T	0.13/1.81	0.13/2.06	0.13/2.27	N/A	ns
		XC6SLX100	−0.14/2.03	−0.14/2.24	−0.14/2.56	−0.17/3.44	ns
		XC6SLX100T	−0.14/2.03	−0.14/2.24	−0.14/2.56	N/A	ns
		XC6SLX150	−0.24/2.42	−0.24/2.74	−0.24/2.95	−0.60/3.75	ns
		XC6SLX150T	−0.24/2.42	−0.24/2.74	−0.24/2.95	N/A	ns
		XA6SLX4	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX9	0.10/1.57	N/A	0.10/1.84	N/A	ns
		XA6SLX16	0.12/1.43	N/A	0.12/1.64	N/A	ns
		XA6SLX25	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX25T	0.18/1.65	N/A	0.18/1.99	N/A	ns
		XA6SLX45	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX45T	−0.08/1.82	N/A	−0.08/2.27	N/A	ns
		XA6SLX75	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XA6SLX100	N/A	N/A	0.10/2.51	N/A	ns
		XQ6SLX75	N/A	N/A	0.13/2.32	−0.12/3.30	ns
		XQ6SLX75T	0.13/2.02	N/A	0.13/2.32	N/A	ns
		XQ6SLX150	N/A	N/A	−0.24/2.95	−0.60/3.75	ns
		XQ6SLX150T	−0.24/2.74	N/A	−0.24/2.95	N/A	ns

Notes:

- Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
- IFF = Input Flip-Flop or Latch.